- Operating Voltage Range of 4.5 V to 5.5 V
- Low Power Consumption, 80- $\mu \mathrm{A}$ Max ICC
- Typical $\mathrm{t}_{\mathrm{pd}}=12 \mathrm{~ns}$
- $\pm 6-\mathrm{mA}$ Output Drive at 5 V
- Low Input Current of $1 \mu \mathrm{~A}$ Max
- Inputs Are TTL-Voltage Compatible

SN54HCT652 . . . JT OR W PACKAGE
SN74HCT652 ... DW OR NT PACKAGE (TOP VIEW)


## - Independent Registers and Enables for $A$ and B Buses

- Multiplexed Real-Time and Stored Data
- True Data Paths
- High-Current 3-State Outputs Can Drive Up To 15 LSTTL Loads

SN54HCT652... FK PACKAGE
(TOP VIEW)


NC - No internal connection

## description/ordering information

The 'HCT652 devices consist of bus-transceiver circuits, D-type flip-flops, and control circuitry arranged for multiplexed transmission of data directly from the data bus or from the internal storage registers. Output-enable ( $O E A B$ and $\overline{O E B A}$ ) inputs are provided to control the transceiver functions. Select-control (SAB and SBA) inputs are provided to select real-time or stored data transfer. A low input level selects real-time data; a high input level selects stored data. Figure 1 illustrates the four fundamental bus-management functions that can be performed with these devices.

ORDERING INFORMATION

| $T_{\mathbf{A}}$ | PACKAGEt |  | ORDERABLE <br> PART NUMBER | TOP-SIDE <br> MARKING |
| :---: | :--- | :--- | :--- | :--- |
|  | PDIP - NT | Tube | SN74HCT652NT | SN74HCT652NT |
|  | SOIC - DW | Tube | SN74HCT652DW | HCT652 |
|  |  | Tape and reel | SN74HCT652DWR |  |
| $-55^{\circ} \mathrm{C}$ to $125^{\circ} \mathrm{C}$ | CDIP - JT | Tube | SNJ54HCT652JT | SNJ54HCT652JT |
|  | CFP - W | Tube | SNJ54HCT652W | SNJ54HCT652W |
|  | LCCC - FK | Tube | SNJ54HCT652FK | SNJ54HCT652FK |

$\dagger$ Package drawings, standard packing quantities, thermal data, symbolization, and PCB design guidelines are available at www.ti.com/sc/package.

## description/ordering information (continued)

Data on the A or B data bus, or both, can be stored in the internal D-type flip-flops by low-to-high transitions at the appropriate clock (CLKAB or CLKBA) terminals, regardless of the select- or output-control terminals. When SAB and SBA are in the real-time transfer mode, it is possible to store data without using the internal D-type flip-flops by simultaneously enabling OEAB and OEBA. In this configuration, each output reinforces its input. When all other data sources to the two sets of bus lines are at high impedance, each set of bus lines remains at its last state.
To ensure the high-impedance state during power up or power down, $\overline{\mathrm{OEBA}}$ should be tied to $\mathrm{V}_{\mathrm{CC}}$ through a pullup resistor and OEAB should be tied to GND through a pulldown resistor; the minimum value of the resistor is determined by the current-sinking/current-sourcing capability of the driver.

FUNCTION TABLE

| INPUTS |  |  |  |  |  | DATA I/O $\dagger$ |  | OPERATION OR FUNCTION |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| OEAB | $\overline{\text { OEBA }}$ | CLKAB | CLKBA | SAB | SBA | A1-A8 | B1-B8 |  |
| L | H | H or L | H or L | X | X | Input | Input | Isolation |
| L | H | $\uparrow$ | $\uparrow$ | X | X | Input | Input | Store $A$ and $B$ data |
| X | H | $\uparrow$ | H or L | X | X | Input | Unspecified $\ddagger$ | Store A, hold B |
| H | H | $\uparrow$ | $\uparrow$ | x $\ddagger$ | X | Input | Output | Store A in both registers |
| L | X | H or L | $\uparrow$ | X | X | Unspecified $\ddagger$ | Input | Hold A, store B |
| L | L | $\uparrow$ | $\uparrow$ | X | X $\ddagger$ | Output | Input | Store B in both registers |
| L | L | X | X | X | L | Output | Input | Real-time B data to A bus |
| L | L | X | H or L | X | H | Output | Input | Stored $B$ data to $A$ bus |
| H | H | X | X | L | X | Input | Output | Real-time $A$ data to $B$ bus |
| H | H | H or L | X | H | X | Input | Output | Stored A data to B bus |
| H | L | H or L | H or L | H | H | Output | Output | Stored $A$ data to $B$ bus and stored $B$ data to $A$ bus |

$\dagger$ The data-output functions can be enabled or disabled by a variety of level combinations at OEAB or $\overline{\mathrm{OEBA}}$. Data-input functions always are enabled; i.e., data at the bus terminals is stored on every low-to-high transition on the clock inputs.
$\ddagger$ Select control = L: clocks can occur simultaneously.
Select control = H: clocks must be staggered to load both registers.


Pin numbers shown are for the DW, JT, NT, and W packages.
Figure 1. Bus-Management Functions

## logic diagram (positive logic)



Pin numbers shown are for the DW, JT, NT, and W packages.

## absolute maximum ratings over operating free-air temperature range (unless otherwise noted) $\dagger$

$$
\begin{aligned}
& \text { Input clamp current, } \mathrm{I}_{\mathrm{IK}}\left(\mathrm{~V}_{\mathrm{I}}<0 \text { or } \mathrm{V}_{\mathrm{I}}>\mathrm{V}_{\mathrm{CC}}\right) \text { (see Note 1) . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . } \pm 20 \mathrm{~mA}
\end{aligned}
$$

$$
\begin{aligned}
& \text { Continuous output current, } \mathrm{I}_{\mathrm{O}}\left(\mathrm{~V}_{\mathrm{O}}=0 \text { to } \mathrm{V}_{\mathrm{C}}\right) \text {. . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . } \pm 35 \mathrm{~mA} \\
& \text { Continuous current through } \mathrm{V}_{\mathrm{CC}} \text { or GND . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . } \pm 70 \mathrm{~mA} \\
& \text { Package thermal impedance, } \theta_{\text {JA }} \text { (see Note 2): DW package . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . 46} \mathrm{C} / \mathrm{W} \\
& \text { (see Note 3): NT package . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . } 67^{\circ} \mathrm{C} / \mathrm{W} \\
& \text { Storage temperature range, } \mathrm{T}_{\text {stg }} \text {. . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . }-65^{\circ} \mathrm{C} \text { to } 150^{\circ} \mathrm{C} \\
& \dagger \text { Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and } \\
& \text { functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not } \\
& \text { implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability. } \\
& \text { NOTES: 1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed. } \\
& \text { 2. The package thermal impedance is calculated in accordance with JESD 51-7. } \\
& \text { 3. The package thermal impedance is calculated in accordance with JESD 51-3. }
\end{aligned}
$$

## recommended operating conditions (see Note 4)



NOTE 4: All unused inputs of the device must be held at $\mathrm{V}_{\mathrm{CC}}$ or GND to ensure proper device operation. Refer to the TI application report, Implications of Slow or Floating CMOS Inputs, literature number SCBA004.
electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

| PARAMETER |  | TEST CONDITIONS |  | VCC | $\mathrm{T}_{\mathrm{A}}=25^{\circ} \mathrm{C}$ |  |  | SN54HCT652 | SN74HCT652 | UNIT |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  |  | MIN | TYP |  | MAX | MIN MAX | MIN MAX |  |
| VOH |  |  |  | $\mathrm{V}_{\mathrm{I}}=\mathrm{V}_{\mathrm{IH}}$ or $\mathrm{V}_{\mathrm{IL}}$ | $\mathrm{IOH}=-20 \mu \mathrm{~A}$ | 4.5 V | 4.4 | 4.499 |  | 4.4 | 4.4 | V |
|  |  | $\mathrm{OH}=-6 \mathrm{~mA}$ | 3.98 |  | 4.3 |  |  | 3.7 | 3.84 |  |  |
| $\mathrm{V}_{\mathrm{OL}}$ |  | $\mathrm{V}_{\mathrm{I}}=\mathrm{V}_{\mathrm{IH}}$ or $\mathrm{V}_{\mathrm{IL}}$ | $\mathrm{IOL}=20 \mu \mathrm{~A}$ | 4.5 V |  | 0.001 | 0.1 | 0.1 | 0.1 | V |  |
|  |  | $\mathrm{IOL}=6 \mathrm{~mA}$ |  |  | 0.17 | 0.26 | 0.4 | 0.33 |  |  |  |
| 1 | Control inputs |  | $\mathrm{V}_{\mathrm{I}}=\mathrm{V}_{\text {CC }}$ or 0 |  | 5.5 V |  | $\pm 0.1$ | $\pm 100$ | $\pm 1000$ | $\pm 1000$ | nA |  |
| Ioz | A or B | $\begin{aligned} & \mathrm{V}_{\mathrm{O}}=\mathrm{V}_{\mathrm{CC}} \text { or } 0, \\ & \text { Data }=\mathrm{V}_{\mathrm{CC}} \text { or } 0 \end{aligned}$ | $\mathrm{V}_{\mathrm{I}}=\mathrm{V}_{\mathrm{IH}} \text { or } \mathrm{V}_{\mathrm{IL}},$ | 5.5 V |  | $\pm 0.01$ | $\pm 0.5$ | $\pm 10$ | $\pm 5$ | $\mu \mathrm{A}$ |  |
| ICC |  | $\mathrm{V}_{\mathrm{I}}=\mathrm{V}_{\mathrm{CC}}$ or 0 , | $\mathrm{l}=0$ | 5.5 V |  |  | 8 | - 160 | 80 | $\mu \mathrm{A}$ |  |
| ${ }^{\Delta} \mathrm{CCC}^{\dagger}$ |  | One input at 0.5 Other inputs at | V or 2.4 V , or $\mathrm{V}_{\mathrm{CC}}$ | 5.5 V |  | 1.4 | 2.4 | Q 3 | 2.9 | mA |  |
| $\mathrm{C}_{i}$ | Control inputs |  |  | $\begin{gathered} 4.5 \mathrm{~V} \\ \text { to } 5.5 \mathrm{~V} \end{gathered}$ |  | 3 | 10 | 10 | 10 | pF |  |

$\dagger$ This is the increase in supply current for each input that is at one of the specified TTL voltage levels, rather than 0 V or $\mathrm{V}_{\mathrm{CC}}$.
timing requirements over recommended operating free-air temperature range (unless otherwise noted)

|  |  | VCC | $\mathrm{T}_{\mathrm{A}}=25^{\circ} \mathrm{C}$ |  | SN54HCT652 |  | SN74HCT652 |  | UNIT |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  |  | MIN | MAX | MIN | MAX | MIN | MAX |  |
| ${ }^{\text {f }}$ clock | Clock frequency |  | 4.5 V |  | 25 |  | 17 |  | 20 | MHz |
|  |  | 5.5 V |  | 28 |  | 19 |  | 22 |  |  |
| $\mathrm{t}_{\mathrm{w}}$ | Pulse duration, CLKBA or CLKAB high or low | 4.5 V | 20 |  |  |  | 25 |  | ns |  |
|  |  | 5.5 V | 18 |  |  |  | 23 |  |  |  |
| $\mathrm{t}_{\text {su }}$ | Setup time, A before CLKAB $\uparrow$ or B before CLKBA $\uparrow$ | 4.5 V | 15 |  | 23 |  | 19 |  | ns |  |
|  |  | 5.5 V | 14 |  | 21 |  | 17 |  |  |  |
| $t_{h}$ | Hold time, A after CLKAB $\uparrow$ or B after CLKBA $\uparrow$ | 4.5 V | 5 |  | 5 |  | 5 |  | ns |  |
|  |  | 5.5 V | 5 |  | 5 |  | 5 |  |  |  |

switching characteristics over recommended operating free-air temperature range, $\mathrm{C}_{\mathrm{L}}=50 \mathrm{pF}$ (unless otherwise noted) (see Figure 2)

| PARAMETER | FROM (INPUT) | $\begin{gathered} \text { TO } \\ \text { (OUTPUT) } \end{gathered}$ | Vcc | $\mathrm{T}_{\mathrm{A}}=25^{\circ} \mathrm{C}$ |  |  | SN54HCT652 |  | SN74HCT652 |  | UNIT |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  |  |  |  | MIN | TYP | MAX | MIN | MAX | MIN | MAX |  |
| ${ }^{\text {fmax }}$ |  |  | 4.5 V | 25 | 35 |  | 17 |  | 20 |  | MHz |
|  |  |  | 5.5 V | 28 | 40 |  | 19 |  | 22 |  |  |
| ${ }^{\text {tpd }}$ | CLKBA or CLKAB | A or B | 4.5 V |  | 18 | 36 |  | 54 |  | 45 | ns |
|  |  |  | 5.5 V |  | 16 | 32 |  | 49 |  | 41 |  |
|  | A or B | B or A | 4.5 V |  | 14 | 27 |  | 41 |  | 34 |  |
|  |  |  | 5.5 V |  | 12 | 24 |  | - 37 |  | 31 |  |
|  | SBA or SAB $\dagger$ | A or B | 4.5 V |  | 20 | 38 |  | 57 |  | 48 |  |
|  |  |  | 5.5 V |  | 17 | 34 | 3 | 51 |  | 43 |  |
| ten | $\overline{\text { OEBA }}$ or OEAB | $A$ or $B$ | 4.5 V |  | 25 | 49 |  | 74 |  | 61 | ns |
|  |  |  | 5.5 V |  | 22 | 44 | Q | 67 |  | 55 |  |
| ${ }^{\text {dis }}$ | $\overline{\text { OEBA }}$ or OEAB | A or B | 4.5 V |  | 25 | 49 |  | 74 |  | 61 | ns |
|  |  |  | 5.5 V |  | 22 | 44 |  | 67 |  | 55 |  |
| $t_{t}$ |  | Any | 4.5 V |  | 9 | 12 |  | 18 |  | 15 | ns |
|  |  |  | 5.5 V |  | 7 | 11 |  | 16 |  | 14 |  |

$\dagger$ These parameters are measured with the internal output state of the storage register opposite that of the bus input.
switching characteristics over recommended operating free-air temperature range, $\mathrm{C}_{\mathrm{L}}=150 \mathrm{pF}$ (unless otherwise noted) (see Figure 2)

| PARAMETER | FROM (INPUT) | TO (OUTPUT) | Vcc | $\mathrm{T}_{\mathrm{A}}=25^{\circ} \mathrm{C}$ |  |  | SN54HCT652 | SN74HCT652 | UNIT |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  |  |  |  | MIN | TYP | MAX | MIN MAX | MIN MAX |  |
| ${ }^{\text {tpd }}$ | CLKBA or CLKAB | $A$ or B | 4.5 V |  | 24 | 53 | 80 | 66 | ns |
|  |  |  | 5.5 V |  | 22 | 47 | 72 | 60 |  |
|  | $A$ or B | B or A | 4.5 V |  | 22 | 44 | 70 | 55 |  |
|  |  |  | 5.5 V |  | 20 | 39 | -60 | 50 |  |
|  | SBA or SAB ${ }^{\dagger}$ | $A$ or $B$ | 4.5 V |  | 26 | 55 | - 83 | 69 |  |
|  |  |  | 5.5 V |  | 24 | 49 | ) 74 | 62 |  |
| ten | $\overline{\text { OEBA }}$ or OEAB | A or B | 4.5 V |  | 33 | 66 | \% 100 | 82 | ns |
|  |  |  | 5.5 V |  | 30 | 59 | $Q \quad 90$ | 74 |  |
| $t_{t}$ |  | Any | 4.5 V |  | 17 | 42 | 63 | 53 | ns |
|  |  |  | 5.5 V |  | 14 | 38 | 57 | 48 |  |

$\dagger$ These parameters are measured with the internal output state of the storage register opposite that of the bus input.
operating characteristics, $\mathrm{T}_{\mathrm{A}}=25^{\circ} \mathrm{C}$

| PARAMETER | TEST CONDITIONS | TYP | UNIT |  |
| :---: | :---: | :---: | :---: | :---: |
| $\mathrm{C}_{\text {pd }}$ | Power dissipation capacitance | No load | 50 | pF |

## PARAMETER MEASUREMENT INFORMATION



LOAD CIRCUIT


VOLTAGE WAVEFORMS SETUP AND HOLD AND INPUT RISE AND FALL TIMES


VOLTAGE WAVEFORMS
PROPAGATION DELAY AND OUTPUT RISE AND FALL TIMES


VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES FOR 3-STATE OUTPUTS

NOTES: A. $C_{L}$ includes probe and test-fixture capacitance.
B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
C. Phase relationships between waveforms were chosen arbitrarily. All input pulses are supplied by generators having the following characteristics: $\mathrm{PRR} \leq 1 \mathrm{MHz}, \mathrm{Z}_{\mathrm{O}}=50 \Omega, \mathrm{t}_{\mathrm{r}}=6 \mathrm{~ns}, \mathrm{t}_{\mathrm{f}}=6 \mathrm{~ns}$.
D. For clock inputs, $f_{\max }$ is measured when the input duty cycle is $50 \%$.
E. The outputs are measured one at a time with one input transition per measurement.
F. tPLZ and $\mathrm{tPHZ}^{2}$ are the same as $\mathrm{t}_{\text {dis }}$.
G. tPZL and tPZH are the same as ten.
H. $\mathrm{t}_{\mathrm{PLH}}$ and $\mathrm{t}_{\mathrm{PHL}}$ are the same as $\mathrm{t}_{\mathrm{pd}}$.

Figure 1. Load Circuit and Voltage Waveforms


NOTES: A. All linear dimensions are in inches (millimeters).
B. This drawing is subject to change without notice.


NOTES: A. All linear dimensions are in inches (millimeters).
B. This drawing is subject to change without notice.
C. Body dimensions do not include mold flash or protrusion not to exceed $0.006(0,15)$.
D. Falls within JEDEC MS-013

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